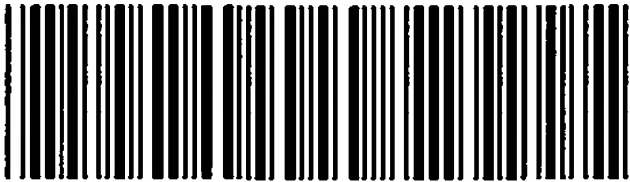


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/655,788	FONG ET AL.	
	Examiner	Art Unit	
	John A. Tweel, Jr.	2636	

SEARCHED			
Class	Subclass	Date	Examiner
340	573.4	6/8/2005	JAT
	539.13	6/8/2005	JAT
	539.15	6/8/2005	JAT
	539.21	6/8/2005	JAT
	539.23	6/8/2005	JAT
	573.1	6/8/2005	JAT
	573.3	6/8/2005	JAT
455	421	6/8/2005	JAT
	134	6/8/2005	JAT
	457	6/8/2005	JAT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR